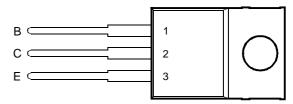
- Rugged Triple-Diffused Planar Construction
- 4 A Continuous Collector Current
- Operating Characteristics Fully Guaranteed at 100°C
- 1200 Volt Blocking Capability
- 75 W at 25°C Case Temperature

#### TO-220 PACKAGE (TOP VIEW)



Pin 2 is in electrical contact with the mounting base.

MDTRACA

# absolute maximum ratings at 25°C case temperature (unless otherwise noted)

RATING	SYMBOL	VALUE	UNIT		
Collector-base voltage (I <sub>E</sub> = 0)	TIPL760B	\/	1100	V	
Collector-base voltage (I <sub>E</sub> = 0)	TIPL760C	V <sub>CBO</sub>	1200	V	
Collector-emitter voltage (V <sub>RF</sub> = 0)	TIPL760B	V	1100	V	
Collector-entitler voltage (V <sub>BE</sub> = 0)	TIPL760C	V <sub>CES</sub>	1200	٧	
Collector-emitter voltage (I <sub>R</sub> = 0)	TIPL760B	\/	500	V	
Collector-entitler voltage (IB = 0)	TIPL760C	V <sub>CEO</sub>	550	V	
Emitter-base voltage	V <sub>EBO</sub>	10	V		
Continuous collector current	I <sub>C</sub>	4	Α		
Peak collector current (see Note 1)	I <sub>CM</sub>	8	Α		
Continuous device dissipation at (or below) 25°C case temperature	P <sub>tot</sub>	75	W		
Operating junction temperature range	T <sub>j</sub>	-65 to +150	°C		
Storage temperature range	T <sub>stg</sub>	-65 to +150	°C		

NOTE 1: This value applies for  $t_p \le 10$  ms, duty cycle  $\le 2\%$ .



# TIPL760B, TIPL760C NPN SILICON POWER TRANSISTORS

MAY 1989 - REVISED MARCH 1997

# electrical characteristics at 25°C case temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS				MIN	TYP	MAX	UNIT	
V <sub>CEO(sus)</sub>	Collector-emitter sustaining voltage	I <sub>C</sub> =	10 mA	L = 25 mH	(see Note 2)	TIPL760B TIPL760C	500 550			V
I <sub>CES</sub>	Collector-emitter cut-off current	~-	1200 V 1100 V 1200 V	$V_{BE} = 0$ $V_{BE} = 0$ $V_{BE} = 0$ $V_{BE} = 0$	T <sub>C</sub> = 100°C T <sub>C</sub> = 100°C	TIPL760B TIPL760C TIPL760B TIPL760C			50 50 200 200	μΑ
I <sub>CEO</sub>	Collector cut-off current	$V_{CE} = V_{CE} = V_{CE}$	500 V 550 V	$I_{B} = 0$ $I_{B} = 0$		TIPL760B TIPL760C			50 50	μΑ
I <sub>EBO</sub>	Emitter cut-off current	V <sub>EB</sub> =	10 V	I <sub>C</sub> = 0					1	mA
h <sub>FE</sub>	Forward current transfer ratio	V <sub>CE</sub> =	5 V	I <sub>C</sub> = 0.5 A	(see Notes 3 ar	nd 4)	20		60	
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	I <sub>B</sub> = I <sub>B</sub> = I <sub>B</sub> =	0.4 A 0.6 A 0.6 A	$I_{C} = 2 A$ $I_{C} = 3 A$ $I_{C} = 3 A$	(see Notes 3 ar	nd 4)			1.0 2.5 5.0	٧
V <sub>BE(sat)</sub>	Base-emitter saturation voltage	I <sub>B</sub> = I <sub>B</sub> = I <sub>B</sub> =	0.4 A 0.6 A 0.6 A	$I_{C} = 2 A$ $I_{C} = 3 A$ $I_{C} = 3 A$	(see Notes 3 ar	nd 4)			1.2 1.4 1.3	٧
f <sub>t</sub>	Current gain bandwidth product	V <sub>CE</sub> =	10 V	I <sub>C</sub> = 0.5 A	f = 1 MHz			12		MHz
C <sub>ob</sub>	Output capacitance	V <sub>CB</sub> =	20 V	I <sub>E</sub> = 0	f = 0.1 MHz			110		pF

NOTES: 2. Inductive loop switching measurement.

- 3. These parameters must be measured using pulse techniques,  $t_p$  = 300  $\mu s$ , duty cycle  $\leq$  2%.
- 4. These parameters must be measured using voltage-sensing contacts, separate from the current carrying contacts.

# thermal characteristics

	PARAMETER			MAX	UNIT
$R_{\theta JC}$	Junction to case thermal resistance			1.56	°C/W

# inductive-load-switching characteristics at 25°C case temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS †			MIN	TYP	MAX	UNIT
t <sub>sv</sub>	Voltage storage time	I <sub>C</sub> = 3 A V <sub>BE(off)</sub> = -5 V	I <sub>B(on)</sub> = 0.6 A				2.5	μs
t <sub>rv</sub>	Voltage rise time			(see Figures 1 and 2)			300	ns
t <sub>fi</sub>	Current fall time						250	ns
t <sub>ti</sub>	Current tail time						150	ns
t <sub>xo</sub>	Cross over time						400	ns
t <sub>sv</sub>	Voltage storage time	I <sub>C</sub> = 3 A V <sub>BE(off)</sub> = -5 V	$I_{B(on)} = 0.6 \text{ A}$ $T_C = 100^{\circ}\text{C}$ (see	(see Figures 1 and 2)			3	μs
t <sub>rv</sub>	Voltage rise time						500	ns
t <sub>fi</sub>	Current fall time						250	ns
t <sub>ti</sub>	Current tail time						150	ns
t <sub>xo</sub>	Cross over time						750	ns

<sup>&</sup>lt;sup>†</sup> Voltage and current values shown are nominal; exact values vary slightly with transistor parameters.

## PARAMETER MEASUREMENT INFORMATION

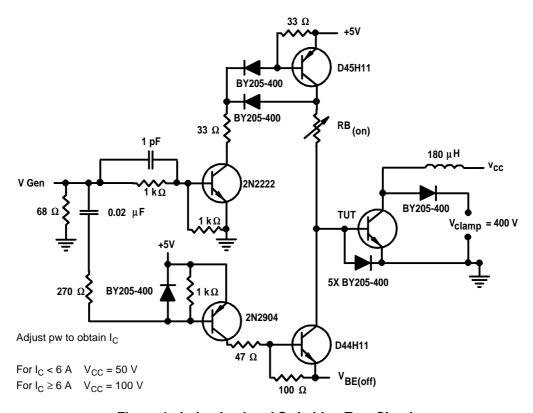
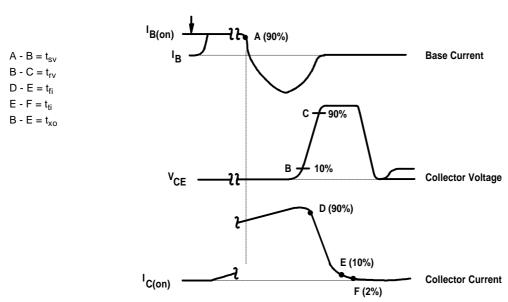


Figure 1. Inductive-Load Switching Test Circuit



NOTES: A. Waveforms are monitored on an oscilloscope with the following characteristics:  $t_r < 15$  ns,  $R_{in} > 10 \Omega$ ,  $C_{in} < 11.5$  pF. B. Resistors must be noninductive types.

Figure 2. Inductive-Load Switching Waveforms



#### TYPICAL CHARACTERISTICS

# **TYPICAL DC CURRENT GAIN COLLECTOR CURRENT** TCP741AA 100 = 125°C 25°C -65°C hFE - Typical DC Current Gain V<sub>CE</sub> = 5 V 10 1.0 0.1 1.0 10 I<sub>c</sub> - Collector Current - A Figure 3.

# **COLLECTOR-EMITTER SATURATION VOLTAGE**

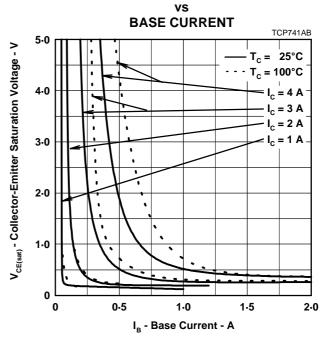
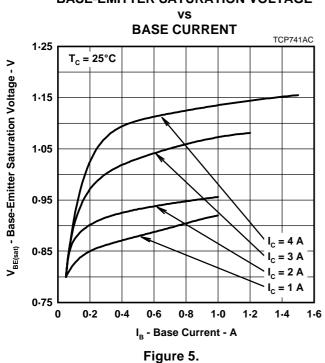


Figure 4.

# **BASE-EMITTER SATURATION VOLTAGE**



## COLLECTOR CUT-OFF CURRENT

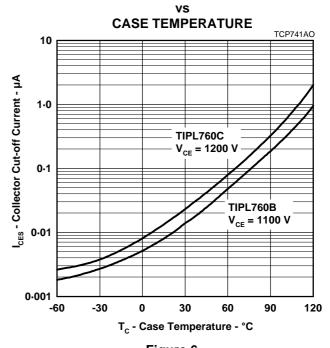
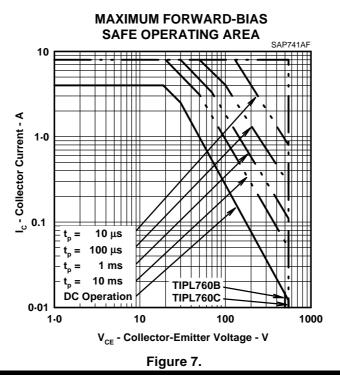


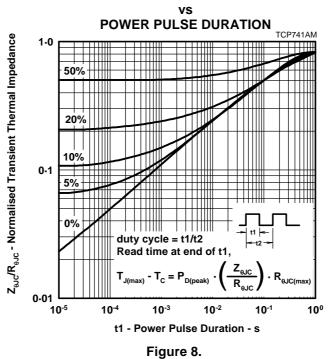
Figure 6.

## **MAXIMUM SAFE OPERATING REGIONS**



# THERMAL INFORMATION

#### THERMAL RESPONSE JUNCTION TO CASE

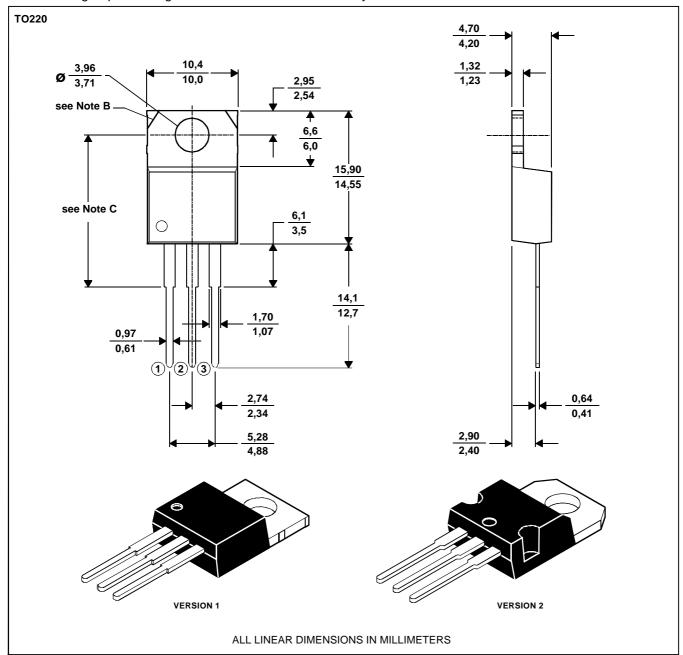


#### **MECHANICAL DATA**

## **TO-220**

# 3-pin plastic flange-mount package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



NOTES: A. The centre pin is in electrical contact with the mounting tab.

- B. Mounting tab corner profile according to package version.
- C. Typical fixing hole centre stand off height according to package version. Version 1, 18.0 mm. Version 2, 17.6 mm.

**MDXXBE** 

## PRODUCT INFORMATION

MAY 1989 - REVISED MARCH 1997

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